

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.014384.1		APPLICATION NO. 10/775181 NYA	
				APPLICANT MASAFUMI KYOGAKU ET AL.			
				FILING DATE FILED HEREWITH		GROUP 2879 2878	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>AW</i>	6,472,814	10/02	Yamanobe	313	495		
<i>AW</i>	6,184,610	2/01	Shibata et al.	313	309		
<i>AW</i>	6,246,168	6/01	Kishi et al.	313	495		
<i>AW</i>	6,626,719	9/03	Ono et al.	445	24		
<i>AW</i>	6,288,494	9/01	Tuskamoto et al.	315	169.1		
<i>AW</i>	5,645,462	7/97	Banno et al.	445	51		
<i>AW</i>	6,435,928 B1	8/02	Tsukamoto	445	24		
<i>AW</i>	6,221,426	4/01	Yamanobe	427	77		
<i>AW</i>	6,231,413	9/99	Tsukamoto	445	24		
<i>AW</i>	6,169,356	1/01	Ohnishi et al.	313	495		
<i>AW</i>	5,541,752	8/94	Taniguchi et al.	359	78		
<i>AW</i>	5,805,129	12/95	Inaba et al.	345	97		
<i>AW</i>	6,008,502	3/97	Deguchi et al.	257	10		
<i>AW</i>	4,904,895	2/27/90	Tsukamoto et al.	313	336		
EXAMINER Joseph Williams				DATE CONSIDERED 7/7/04			

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FOREIGN PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
JW	64-19657	1/89	Japan			Abstract	
JW	8-273523	10/96	Japan			Abstract	
JW	0 660 357 A1	6/95	EPO				
JW	0 788 130 A2	8/97	EPO				
JW	7-192614	7/95	Japan			Abstract	
JW	7-235255	9/95	Japan			Abstract	
JW	8-007749	1/96	Japan			Abstract	
JW	9-237571	9/97	Japan			Abstract	
JW	0 536 731	4/93	EPO				
JW	0 299 461	1/89	EPO				
JW	0 658 924	6/95	EPO				
JW	0 693 766	1/96	EPO				
JW	0 696 813	2/96	EPO				
JW	0 701 265	3/96	EPO				
JW	0 715 329	6/96	EPO				
JW	0 736 890	10/96	EPO				
JW	0 736 892	10/96	EPO				
JW	0 740 342	10/96	EPO				
JW	0 757 371	2/97	EPO				
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER Joseph Williams				DATE CONSIDERED 7/7/04			

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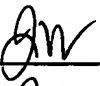



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FOREIGN PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
<i>JW</i>	1-309242	12/89	Japan	_____	_____	Translation	
<i>JW</i>	9-102267	4/15	Japan	_____	_____	Abstract	
<i>JW</i>	97-71896	11/97	Korea	_____	_____	Abstract	
<i>JW</i>	9-326241	12/97	Japan	_____	_____	Abstract	
<i>JW</i>	0 309 242	3/89	EPO	_____	_____		
<i>JW</i>	8-264112	10/96	Japan	_____	_____	Abstract	
<i>JW</i>	8-162015	6/96	Japan	_____	_____	Abstract	
<i>JW</i>	9-27268	1/97	Japan	_____	_____	Abstract	
<i>JW</i>	9-27272	1/97	Japan	_____	_____	Abstract	
<i>JW</i>	10-3848	1/98	Japan	_____	_____	Abstract	
<i>JW</i>	10-3847	1/98	Japan	_____	_____	Abstract	
<i>JW</i>	10-3853	1/98	Japan	_____	_____	Abstract	
<i>JW</i>	10-3854	1/98	Japan	_____	_____	Abstract	

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
<i>JW</i>	Patent Abstracts of Japan, Vol. 14, No. 108 (1990) <i>no month</i>
<i>JW</i>	W.P. Dyke et al., "Field Emission," Advances in Electronics and Electron Physics, Vol. VIII, 1956, pp. 89-185. <i>no month</i>
<i>JW</i>	H. Araki, et al., "Electroforming and Electron Emission of Carbon Thin Films," Journal of the Vacuum Soc. of Japan, Vol. 2-6, No. 1, 1983, pp. 22-29 (with English Abstract on p. 22). <i>no month</i>

EXAMINER <i>Joseph Williams</i>	DATE CONSIDERED <i>7/8/04</i>
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		G. Dittmer, "Electrical Conduction and Electron Emission of Discontinuous Thin Films," Thin Solid Films, 9, 1972 pp. 317-328. <i>no month</i>					
		M. Elinson, et al. "The Emission of Hot Electrons and the Field Emissions of Electrons From Tin Oxide," Radio Engineering and Electronic Physics, July 1965, pp. 1290-1298.					
		C.A. Mead, "Operation of Tunnel-Emission Devices," J. Applied Physics, Vol. 32, No. 4, April 1961, pp. 646-652.					
		C.A. Spindt et al., "Physical Properties of Thin Films of Thin-film Field Emission Cathodes with Molybdenum Cases," J. Applied Physics, Vol. 47, No. 12, Dec. 1976, pp. 5248-5263.					
		M. Hartwell et al., "Strong Electron Emission From Patterned Tin-Indium Oxide Films," IEDM, 1975, pp. 519-521. <i>no month</i>					
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